



## IEEE standard test access port and boundary-scan architecture : IEEE Std 1149.1- 1990 (includes IEEE Std 1149.1 a-1993) /

IEEE,  
cop. 1993

Normas técnicas.

Monografía

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**Título:** IEEE standard test access port and boundary-scan architecture IEEE Std 1149.1-1990 (includes IEEE Std 1149.1a-1993) [approved by] IEEE Standards Board

**Editorial:** New York IEEE cop. 1993

**Descripción física:** 1 v. il., gráf. 28 cm

**Nota general:** "Sponsored by the Test Technology Standards Committee of the IEEE Computer Society"

**ISBN:** 1-55937-350-4

**Materia:** Normas IEEE. Circuitos impresos. Circuitos integrados. Ingeniería eléctrica.

**Entidades:** IEEE Standards Board IEEE Computer Society. Test Technology Standards Committee

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